# Single-Channel Transient Voltage Suppressor

#### **Product Description**

ON Semiconductor's CM6136 is an *Application Specific Integrated* Passive<sup>m</sup> (ASIP<sup>m</sup>) component in a 2 x 2, 4–bump, 0.4 mm pitch, CSP form factor. This device is designed for:

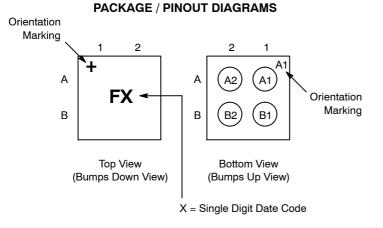
- Fuse
- Transient Voltage Suppression (TVS)
- Electrostatic Discharge Protection
- Electrical Overstress Protection

#### Features

- 4-Bump, 0.8 mm X 0.8 mm Footprint Chip Scale Package (CSP)
- These Devices are Pb-Free and are RoHS Compliant

#### Table 1. PIN DESCRIPTIONS

4-bump CSP Package			
Pin Description			
A1	Fuse Terminal 1		
A2	TVS Channel / Fuse Terminal 2		
B1 & B2	B1 & B2 Device Ground		



4-Bump CSP Package



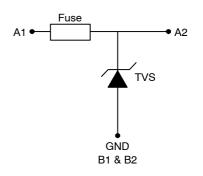
# **ON Semiconductor®**

http://onsemi.com



WLCSP4 CP SUFFIX CASE 567CA

## **ELECTRICAL SCHEMATIC**



## MARKING DIAGRAM



### **ORDERING INFORMATION**

Device	Package	Shipping <sup>†</sup>
CM6136	WLCSP4 (Pb-Free)	10,000/Tape & Reel

+ For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specification Brochure, BRD8011/D.

## CM6136

## **ELECTRICAL SPECIFICATIONS AND CONDITIONS**

#### **Table 2. ABSOLUTE RATINGS**

Parameter	Rating	Units
Failing to nonconductive, $I^2t$ – from <b>A1</b> pin to device ground (Maximum I <sub>PP</sub> value using 10/1000 $\mu$ s pulse). See Notes 1 and 2.	4	A
Failing to nonconductive, $I^{2}t$ – from <b>A2</b> pin to device ground (Maximum I <sub>PP</sub> value using 10/1000 µs pulse). See Notes 1 and 2.	50	A

1. The device must not burn to open-circuit, when the value is below maximum  $I_{PP}$ 

2. This parameter is characterized at 25°C using an ON Semiconductor-specific test board.

#### **Table 3. PARAMETERS AND OPERATING CONDITIONS**

Parameter	Rating	Units
Storage Temperature Range	-55 to +150	°C
Operating Temperature Range	-30 to +85	°C

#### Table 4. ELECTRICAL OPERATING CHARACTERISTICS (Note 1)

Symbol	Parameter	Conditions	Min	Тур	Max	Units
R	Resistance A1 – A2	B1 and B2 floating (Note 2)			50	mΩ
R <sub>OPEN</sub>	Resistance after open fuse	B1 and B2 floating	1			MΩ
t <sub>FUSE</sub>	Fusing time	B1 and B2 floating; I = 5 A (Note 3)			100	ms
t <sub>LIFE</sub>	Fuse life time	B1 and B2 floating; I = 2 A (Notes 3, 4 and 9)	4000			Hours
I <sub>OFF</sub>	Stand-off quiescent current	From A1 pin to B1 and B2 pins; Stand-off voltage V <sub>OFF</sub> = 12 V			100	nA
V <sub>BR</sub>	Break down voltage	From A1 pin to B1 and B2 pins; Break down current I <sub>BR</sub> = 20 mA (Note 6)	15.5			V
V <sub>CL</sub>	Clamping voltage during transient	From A1 pin to B1 and B2 pins; Clamping current I <sub>CL</sub> = 1 A (Notes 6 and 7)			19.5	V
V <sub>F</sub>	Forward voltage	From A1 pin to B1 and B2 pins; Forward current $I_F = 850 \text{ mA}$			1.3	V
C <sub>L1</sub>	Line capacitance	V <sub>BIAS</sub> = 0 V		190		pF
C <sub>L2</sub>		V <sub>BIAS</sub> = 5 V	73	92		pF
V <sub>ESD</sub>	ESD protection peak discharge Voltage at <b>A1 pin or A2 to B1 and B2</b> a) Contact Discharge per IEC 61000-4-2	(Note 8)	±30			kV
	b) Air Discharge per IEC 61000-4-2 standard		±30			
f <sub>C</sub>	Minimum attenuation Freq = 80 MHz - 1 GHz Freq = 1 - 4 GHz	$R_{SOURCE} = R_{LOAD} = 50 \ \Omega$		8 20		dB

1. All parameters specified for  $T_A = 25^{\circ}C$  unless otherwise noted. Characterization data for DC parameters is taken from  $-30^{\circ}C$  to  $85^{\circ}C$ . 2. This parameter is measured using low current to avoid self-heating.

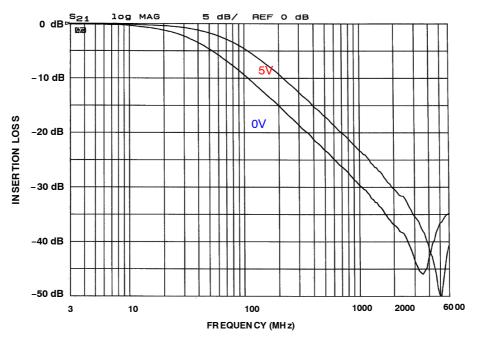
2. This parameter is measured using low current to avoid self-nearing. 3. These parameters are characterized using ON Semiconductor–specific test boards. 4. Fuse is considered failed when its resistance is higher than 1  $\Omega$ . 5. Cumulative distribution of V<sub>BR</sub> between 15.5 V and 16.0 V is about 4.5%. 6. Transient: 8 x 20 µs current pulse.

Transferrer of V<sub>CL</sub> between 19.0 V and 19.5 V is about 4.5%.
Standard IEC 61000-4-2 with C<sub>Discharge</sub> = 150 pF, R<sub>Discharge</sub> = 330 Ω.
Fuse lifetime is extrapolated from Accelerated Life Test (ALT) at 125°C.

# CM6136

## **RF CHARACTERISTICS**

## $T_A = 25^{\circ}C$ , 50 $\Omega$ Environment

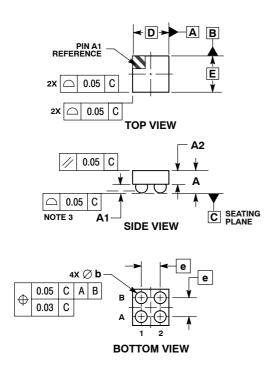




#### CM6136

#### PACKAGE DIMENSIONS

WLCSP4, 0.8x0.8 CASE 567CA-01 **ISSUE O** 

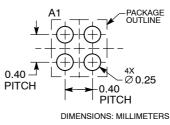


NOTES

- DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.
- CONTROLLING DIMENSION: MILLIMETERS. COPLANARITY APPLIES TO SPHERICAL CROWNS OF SOLDER BALLS. 2. 3.

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	MILLIMETERS		
DIM	MIN	MAX	
Α	0.47	0.53	
A1	0.17	0.24	
A2	0.30 REF		
b	0.24	0.29	
D	0.80 BSC 0.80 BSC		
E			
е	0.40 BSC		

#### RECOMMENDED SOLDERING FOOTPRINT\*



\*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

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